





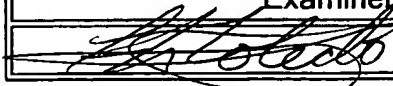






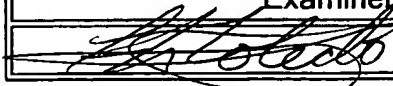










ELECTRONIC INFORMATION DISCLOSURE STATEMENT

Electronic Version v18
Stylesheet Version v18.0

Title of Invention	Real-Time Gate Etch Critical Dimension Control by Oxygen Monitoring																																																				
<p>Application Number: 10/675572 </p> <p>Confirmation Number: 9966</p> <p>First Named Applicant: Gerald Gibson</p> <p>Attorney Docket Number: 075903-208</p> <p>Art Unit: 2812</p> <p>Search string: (6245581 or 6294465 or 6368879 or 6461878 or 6465356).pn.</p> <p>US Patent Documents</p> <p>Note: Applicant is not required to submit a paper copy of cited US Patent Documents</p> <table border="1"><thead><tr><th>init</th><th>Cite.No.</th><th>Patent No.</th><th>Date</th><th>Patentee</th><th>Kind</th><th>Class</th><th>Subclass</th></tr></thead><tbody><tr><td></td><td>1</td><td>6245581</td><td>2001-06-12</td><td>Bonser, et al</td><td></td><td></td><td></td></tr><tr><td></td><td>2</td><td>6294465</td><td>2001-09-25</td><td>Hernandez, et al</td><td></td><td></td><td></td></tr><tr><td></td><td>3</td><td>6368879</td><td>2002-04-09</td><td>Toprac</td><td></td><td></td><td></td></tr><tr><td></td><td>4</td><td>6461878</td><td>2002-10-08</td><td>Lansford</td><td></td><td></td><td></td></tr><tr><td></td><td>5</td><td>6465356</td><td>2002-10-15</td><td>Kim, et al</td><td></td><td></td><td></td></tr></tbody></table> <p>Signature</p> <table border="1"><tr><td>Examiner Name</td><td>Date</td></tr><tr><td></td><td></td></tr></table>		init	Cite.No.	Patent No.	Date	Patentee	Kind	Class	Subclass		1	6245581	2001-06-12	Bonser, et al					2	6294465	2001-09-25	Hernandez, et al					3	6368879	2002-04-09	Toprac					4	6461878	2002-10-08	Lansford					5	6465356	2002-10-15	Kim, et al				Examiner Name	Date		
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